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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

D	eta	ils

E·XFI

Details	
Product Status	Obsolete
Number of LABs/CLBs	2880
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	111
Number of Gates	48000
Voltage - Supply	2.25V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	144-LBGA
Supplier Device Package	144-FPBGA (13x13)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a54sx32a-1fg144

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



Temperature Grade Offering

Package	A54SX08A	A54SX16A	A54SX32A	A54SX72A
PQ208	C,I,A,M	C,I,A,M	C,I,A,M	C,I,A,M
TQ100	C,I,A,M	C,I,A,M	C,I,A,M	
TQ144	C,I,A,M	C,I,A,M	C,I,A,M	
TQ176			C,I,M	
BG329			C,I,M	
FG144	C,I,A,M	C,I,A,M	C,I,A,M	
FG256		C,I,A,M	C,I,A,M	C,I,A,M
FG484			C,I,M	C,I,A,M
CQ208			C,M,B	C,M,B
CQ256			C,M,B	C,M,B

Notes:

1. C = Commercial

- 2. I = Industrial
- 3. A = Automotive
- 4. M = Military
- 5. B = MIL-STD-883 Class B

6. For more information regarding automotive products, refer to the SX-A Automotive Family FPGAs datasheet.

7. For more information regarding Mil-Temp and ceramic packages, refer to the HiRel SX-A Family FPGAs datasheet.

Speed Grade and Temperature Grade Matrix

	F	Std	-1	-2	-3
Commercial	1	1	1	1	Discontinued
Industrial		1	1	1	Discontinued
Automotive		1			
Military		1	1		
MIL-STD-883B		1	1		

Notes:

1. For more information regarding automotive products, refer to the SX-A Automotive Family FPGAs datasheet.

2. For more information regarding Mil-Temp and ceramic packages, refer to the HiRel SX-A Family FPGAs datasheet.

Contact your Actel Sales representative for more information on availability.



Figure 1-5 • DirectConnect and FastConnect for Type 1 SuperClusters



Figure 1-6 • DirectConnect and FastConnect for Type 2 SuperClusters

JTAG Instructions

Table 1-7 lists the supported instructions with the corresponding IR codes for SX-A devices.

Table 1-8 lists the codes returned after executing the IDCODE instruction for SX-A devices. Note that bit 0 is always '1'. Bits 11-1 are always '02F', which is the Actel manufacturer code.

Table 1-7 •	JTAG	Instruction	Code
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Instructions (IR4:IR0)	Binary Code
EXTEST	00000
SAMPLE/PRELOAD	00001
INTEST	00010
USERCODE	00011
IDCODE	00100
HighZ	01110
CLAMP	01111
Diagnostic	10000
BYPASS	11111
Reserved	All others

Table 1-8 • JTAG Instruction Code

Device	Process	Revision	Bits 31-28	Bits 27-12
A54SX08A	0.22 µ	0	8, 9	40B4, 42B4
		1	А, В	40B4, 42B4
A54SX16A	0.22 µ	0	9	4088, 4288
		1	В	4088, 4288
	0.25 µ	1	В	22B8
A54SX32A	0.2 2µ	0	9	40BD, 42BD
		1	В	40BD, 42BD
	0.25 µ	1	В	22BD
A54SX72A	0.22 µ	0	9	40B2, 42B2
		1	В	40B2, 42B2
	0.25 µ	1	В	22B2



Probing Capabilities

SX-A devices also provide an internal probing capability that is accessed with the JTAG pins. The Silicon Explorer II diagnostic hardware is used to control the TDI, TCK, TMS, and TDO pins to select the desired nets for debugging. The user assigns the selected internal nets in Actel Silicon Explorer II software to the PRA/PRB output pins for observation. Silicon Explorer II automatically places the device into JTAG mode. However, probing functionality is only activated when the TRST pin is driven high or left floating, allowing the internal pull-up resistor to pull TRST High. If the TRST pin is held Low, the TAP controller remains in the Test-Logic-Reset state so no probing can be performed. However, the user must drive the TRST pin High or allow the internal pull-up resistor to pull TRST High. When selecting the **Reserve Probe Pin** box as shown in Figure 1-12 on page 1-9, direct the layout tool to reserve the PRA and PRB pins as dedicated outputs for probing. This **Reserve** option is merely a guideline. If the designer assigns user I/Os to the PRA and PRB pins and selects the **Reserve Probe Pin** option, Designer Layout will override the **Reserve Probe Pin** option and place the user I/Os on those pins.

To allow probing capabilities, the security fuse must not be programmed. Programming the security fuse disables the JTAG and probe circuitry. Table 1-9 summarizes the possible device configurations for probing once the device leaves the Test-Logic-Reset JTAG state.

JTAG Mode	TRST ¹	Security Fuse Programmed	PRA, PRB ²	TDI, TCK, TDO ²	
Dedicated	Low	No	User I/O ³	JTAG Disabled	
	High	No	No Probe Circuit Outputs JTAG		
Flexible	Low	No	User I/O ³	User I/O ³	
	High No		Probe Circuit Outputs	JTAG I/O	
		Yes	Probe Circuit Secured	Probe Circuit Secured	

Table 1-9 • Device Configuration Options for Probe Capability (TRST Pin Reserved)

Notes:

1. If the TRST pin is not reserved, the device behaves according to TRST = High as described in the table.

2. Avoid using the TDI, TCK, TDO, PRA, and PRB pins as input or bidirectional ports. Since these pins are active during probing, input signals will not pass through these pins and may cause contention.

3. If no user signal is assigned to these pins, they will behave as unused I/Os in this mode. Unused pins are automatically tristated by the Designer software.

Guidelines for Estimating Power

The following guidelines are meant to represent worst-case scenarios; they can be generally used to predict the upper limits of power dissipation:

Logic Modules (m) = 20% of modules Inputs Switching (n) = Number inputs/4 Outputs Switching (p) = Number of outputs/4 CLKA Loads (q1) = 20% of R-cells CLKB Loads (q2) = 20% of R-cells Load Capacitance (CL) = 35 pF Average Logic Module Switching Rate (fm) = f/10 Average Input Switching Rate (fn) = f/5 Average Output Switching Rate (fp) = f/10 Average CLKA Rate (fq1) = f/2 Average CLKB Rate (fq2) = f/2 Average HCLK Rate (fs1) = f HCLK loads (s1) = 20% of R-cells

To assist customers in estimating the power dissipations of their designs, Actel has published the eX, SX-A and RT54SX-S Power Calculator worksheet.

Theta-JA

Junction-to-ambient thermal resistance (θ_{JA}) is determined under standard conditions specified by JESD-51 series but has little relevance in actual performance of the product in real application. It should be employed with caution but is useful for comparing the thermal performance of one package to another.

A sample calculation to estimate the absolute maximum power dissipation allowed (worst case) for a 329-pin PBGA package at still air is as follows. i.e.:

$$\theta_{JA} = 17.1^{\circ}$$
C/W is taken from Table 2-12 on page 2-11

 $T_A = 125$ °C is the maximum limit of ambient (from the datasheet)

Max. Allowed Power =
$$\frac{\text{Max Junction Temp - Max. Ambient Temp}}{\theta_{JA}} = \frac{150^{\circ}\text{C} - 125^{\circ}\text{C}}{17.1^{\circ}\text{C/W}} = 1.46 \text{ W}$$

EQ 2-11

The device's power consumption must be lower than the calculated maximum power dissipation by the package.

The power consumption of a device can be calculated using the Actel power calculator. If the power consumption is higher than the device's maximum allowable power dissipation, then a heat sink can be attached on top of the case or the airflow inside the system must be increased.

Theta-JC

Junction-to-case thermal resistance (θ_{JC}) measures the ability of a device to dissipate heat from the surface of the chip to the top or bottom surface of the package. It is applicable for packages used with external heat sinks and only applies to situations where all or nearly all of the heat is dissipated through the surface in consideration. If the power consumption is higher than the calculated maximum power dissipation of the package, then a heat sink is required.

Calculation for Heat Sink

For example, in a design implemented in a FG484 package, the power consumption value using the power calculator is 3.00 W. The user-dependent data T_J and T_A are given as follows:

$$T_{J} = 110^{\circ}C$$

 $T_{A} = 70^{\circ}C$

From the datasheet:

 $\theta_{JA} = 18.0^{\circ}C/W$ $\theta_{JC} = 3.2^{\circ}C/W$

$$P = \frac{\text{Max Junction Temp} - \text{Max. Ambient Temp}}{\theta_{JA}} = \frac{110^{\circ}\text{C} - 70^{\circ}\text{C}}{18.0^{\circ}\text{C/W}} = 2.22 \text{ W}$$

EQ 2-12

The 2.22 W power is less than then required 3.00 W; therefore, the design requires a heat sink or the airflow where the device is mounted should be increased. The design's junction-to-air thermal resistance requirement can be estimated by:

$$\theta_{JA} = \frac{Max Junction Temp - Max. Ambient Temp}{P} = \frac{110^{\circ}C - 70^{\circ}C}{3.00 W} = 13.33^{\circ}C/W$$

EQ 2-13



Output Buffer Delays





AC Test Loads



Figure 2-5 • AC Test Loads

Input Buffer Delays



t INY **C-Cell Delays**



Figure 2-6 • Input Buffer Delays

GND

Figure 2-7 • C-Cell Delays

Cell Timing Characteristics

t_{INY}



Figure 2-8 • Flip-Flops

Table 2-17 • A54SX08A Timing Characteristics

(Worst-Case Commercial Condition	s V _{CCA} = 2.25 V, V _{CCI} =	= 4.75 V, T _J = 70°C)
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		-2 S	peed	-1 S	peed	Std. Speed		–F Speed		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Dedicated (H	lardwired) Array Clock Networks									
t _{НСКН}	Input Low to High (Pad to R-cell Input)		1.2		1.3		1.5		2.3	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.0		1.2		1.4		2.0	ns
t _{HPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t _{HPWL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t _{HCKSW}	Maximum Skew		0.4		0.4		0.5		0.8	ns
t _{HP}	Minimum Period	3.2		3.6		4.2		5.8		ns
f _{HMAX}	Maximum Frequency		313		278		238		172	MHz
Routed Arra	y Clock Networks									
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		0.9		1.0		1.2		1.7	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.5		1.7		2.0		2.7	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		0.9		1.0		1.2		1.7	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		1.5		1.7		2.0		2.7	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		1.1		1.3		1.5		2.1	ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		1.6		1.8		2.1		2.9	ns
t _{RPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t _{RPVVL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t _{RCKSW}	Maximum Skew (Light Load)		0.8		0.9		1.1		1.5	ns
t _{RCKSW}	Maximum Skew (50% Load)		0.8		1.0		1.1		1.5	ns
t _{RCKSW}	Maximum Skew (100% Load)		0.9		1.0		1.2		1.7	ns

Table 2-18 A54SX08A Timing Characteristics

		-2 S	peed	-1 S	peed	Std. 9	5peed	-F Speed		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
2.5 V LVCMOS Output Module Timing ^{1,2}		•								
t _{DLH}	Data-to-Pad Low to High		3.9		4.4		5.2		7.2	ns
t _{DHL}	Data-to-Pad High to Low		3.0		3.4		3.9		5.5	ns
t _{DHLS}	Data-to-Pad High to Low—low slew		13.3		15.1		17.7		24.8	ns
t _{ENZL}	Enable-to-Pad, Z to L		2.8		3.2		3.7		5.2	ns
t _{ENZLS}	Data-to-Pad, Z to L—low slew		13.7		15.5		18.2		25.5	ns
t _{ENZH}	Enable-to-Pad, Z to H		3.9		4.4		5.2		7.2	ns
t _{ENLZ}	Enable-to-Pad, L to Z		2.5		2.8		3.3		4.7	ns
t _{ENHZ}	Enable-to-Pad, H to Z		3.0		3.4		3.9		5.5	ns
d _{TLH} ³	Delta Low to High		0.037		0.043		0.051		0.071	ns/pF
d _{THL} ³	Delta High to Low		0.017		0.023		0.023		0.037	ns/pF
d _{THLS} ³	Delta High to Low—low slew		0.06		0.071		0.086		0.117	ns/pF

Note:

1. Delays based on 35 pF loading.

2. The equivalent I/O Attribute Editor settings for 2.5 V LVCMOS is 2.5 V LVTTL in the software.

3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation: Slew Rate [V/ns] = (0.1* V_{CCI} – 0.9* V_{CCI} / (C_{load} * $d_{T[LH|HL|HLS]}$) where C_{load} is the load capacitance driven by the I/O in pF

 $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.

Table 2-21 • A54SX16A Timing Characteristics

(Worst-Case Commercial Conditions, V_{CCA} = 2.25 V, V_{CCI} = 3.0 V, T_J = 70°C)

		-3 Sp	beed ¹	-2 S	peed	–1 S	peed	Std. Speed		-F Speed		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
C-Cell Propa	agation Delays ²											
t _{PD}	Internal Array Module		0.9		1.0		1.2		1.4		1.9	ns
Predicted R	outing Delays ³											
t _{DC}	FO = 1 Routing Delay, Direct Connect		0.1		0.1		0.1		0.1		0.1	ns
t _{FC}	FO = 1 Routing Delay, Fast Connect		0.3		0.3		0.3		0.4		0.6	ns
t _{RD1}	FO = 1 Routing Delay		0.3		0.3		0.4		0.5		0.6	ns
t _{RD2}	FO = 2 Routing Delay		0.4		0.5		0.5		0.6		0.8	ns
t _{RD3}	FO = 3 Routing Delay		0.5		0.6		0.7		0.8		1.1	ns
t _{RD4}	FO = 4 Routing Delay		0.7		0.8		0.9		1		1.4	ns
t _{RD8}	FO = 8 Routing Delay		1.2		1.4		1.5		1.8		2.5	ns
t _{RD12}	FO = 12 Routing Delay		1.7		2		2.2		2.6		3.6	ns
R-Cell Timin	ng											
t _{RCO}	Sequential Clock-to-Q		0.6		0.7		0.8		0.9		1.3	ns
t _{CLR}	Asynchronous Clear-to-Q		0.5		0.6		0.6		0.8		1.0	ns
t _{PRESET}	Asynchronous Preset-to-Q		0.7		0.8		0.8		1.0		1.4	ns
t _{SUD}	Flip-Flop Data Input Set-Up	0.7		0.8		0.9		1.0		1.4		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WASYN}	Asynchronous Pulse Width	1.3		1.5		1.6		1.9		2.7		ns
t _{recasyn}	Asynchronous Recovery Time	0.3		0.4		0.4		0.5		0.7		ns
t _{HASYN}	Asynchronous Removal Time	0.3		0.3		0.3		0.4		0.6		ns
t _{MPW}	Clock Minimum Pulse Width	1.4		1.7		1.9		2.2		3.0		ns
Input Modu	le Propagation Delays											
t _{INYH}	Input Data Pad to Y High 2.5 V LVCMOS		0.5		0.6		0.7		0.8		1.1	ns
t _{INYL}	Input Data Pad to Y Low 2.5 V LVCMOS		0.8		0.9		1.0		1.1		1.6	ns
t _{INYH}	Input Data Pad to Y High 3.3 V PCI		0.5		0.6		0.6		0.7		1.0	ns
t _{INYL}	Input Data Pad to Y Low 3.3 V PCI		0.7		0.8		0.9		1.0		1.4	ns
t _{INYH}	lnput Data Pad to Y High 3.3 V LVTTL		0.7		0.7		0.8		1.0		1.4	ns
t _{INYL}	Input Data Pad to Y Low 3.3 V LVTTL		0.9		1.1		1.2		1.4		2.0	ns

Notes:

1. All –3 speed grades have been discontinued.

2. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.

3. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-24 A54SX16A Timing Characteristics

(Worst-Case Commercial Condition	s V _{CCA} = 2.25 V, V _{CCI} =4.75 V	′, T _J = 70°C)
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		-3 Speed* -2 Speed -		-1 Speed Std. Speed			-F Speed					
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Dedicated	Hardwired) Array Clock Netwo	rks										1
t _{HCKH}	Input Low to High (Pad to R-cell Input)		1.2		1.4		1.6		1.8		2.8	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.0		1.1		1.2		1.5		2.2	ns
t _{HPWH}	Minimum Pulse Width High	1.4		1.7		1.9		2.2		3.0		ns
t _{HPVVL}	Minimum Pulse Width Low	1.4		1.7		1.9		2.2		3.0		ns
t _{HCKSW}	Maximum Skew		0.3		0.3		0.4		0.4		0.7	ns
t _{HP}	Minimum Period	2.8		3.4		3.8		4.4		6.0		ns
f _{HMAX}	Maximum Frequency		357		294		263		227		167	MHz
Routed Arr	ay Clock Networks											1
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		1.0		1.2		1.3		1.6		2.2	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.1		1.3		1.5		1.7		2.4	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		1.1		1.3		1.5		1.7		2.4	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		1.1		1.3		1.5		1.7		2.4	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		1.3		1.5		1.7		2.0		2.8	ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		1.3		1.5		1.7		2.0		2.8	ns
t _{RPWH}	Minimum Pulse Width High	1.4		1.7		1.9		2.2		3.0		ns
t _{RPWL}	Minimum Pulse Width Low	1.4		1.7		1.9		2.2		3.0		ns
t _{RCKSW}	Maximum Skew (Light Load)		0.8		0.9		1.0		1.2		1.7	ns
t _{RCKSW}	Maximum Skew (50% Load)		0.8		0.9		1.0		1.2		1.7	ns
t _{RCKSW}	Maximum Skew (100% Load)		1.0		1.1		1.3		1.5		2.1	ns

Note: **All* –3 speed grades have been discontinued.

Table 2-29 A54SX32A Timing Characteristics

(Worst-Case Commercial Condition	s V _{CCA} = 2.25 V, V _c	_{CCI} = 2.25 V, T _J = 70°C)
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		-3 Sp	beed*	-2 S	peed	-1 S	peed	Std.	Speed	–F S	peed		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units	
Dedicated (Hardwired) Array Clock Networks													
t _{HCKH}	Input Low to High (Pad to R-cell Input)		1.7		2.0		2.2		2.6		4.0	ns	
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.7		2.0		2.2		2.6		4.0	ns	
t _{HPWH}	Minimum Pulse Width High	1.4		1.6		1.8		2.1		2.9		ns	
t _{HPWL}	Minimum Pulse Width Low	1.4		1.6		1.8		2.1		2.9		ns	
t _{HCKSW}	Maximum Skew		0.6		0.6		0.7		0.8		1.3	ns	
t _{HP}	Minimum Period	2.8		3.2		3.6		4.2		5.8		ns	
f _{HMAX}	Maximum Frequency		357		313		278		238		172	MHz	
Routed Arr	ay Clock Networks												
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		2.2		2.5		2.9		3.4		4.7	ns	
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		2.1		2.4		2.7		3.2		4.4	ns	
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		2.4		2.7		3.1		3.6		5.1	ns	
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		2.2		2.5		2.8		3.3		4.6	ns	
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		2.5		2.9		3.2		3.8		5.3	ns	
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		2.4		2.7		3.1		3.6		5.0	ns	
t _{RPWH}	Minimum Pulse Width High	1.4		1.6		1.8		2.1		2.9		ns	
t _{RPWL}	Minimum Pulse Width Low	1.4		1.6		1.8		2.1		2.9		ns	
t _{RCKSW}	Maximum Skew (Light Load)		1.0		1.1		1.3		1.5		2.1	ns	
t _{RCKSW}	Maximum Skew (50% Load)		0.9		1.0		1.2		1.4		1.9	ns	
t _{RCKSW}	Maximum Skew (100% Load)		0.9		1.0		1.2		1.4		1.9	ns	

Note: *All –3 speed grades have been discontinued.

Table 2-31 A54SX32A Timing Characteristics

(Worst-Case Commercial Condition	s V _{CCA} = 2.25 V, V _{CCI} :	= 4.75 V, T _J = 70°C)
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		-3 Sp	-3 Speed* –2 Speed		-1 S	peed	Std.	Speed	-F Speed			
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Dedicated ((Hardwired) Array Clock Netwo	rks										
t _{HCKH}	Input Low to High (Pad to R-cell Input)		1.7		1.9		2.2		2.6		4.0	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.7		2.0		2.2		2.6		4.0	ns
t _{HPWH}	Minimum Pulse Width High	1.4		1.6		1.8		2.1		2.9		ns
t _{HPWL}	Minimum Pulse Width Low	1.4		1.6		1.8		2.1		2.9		ns
t _{HCKSW}	Maximum Skew		0.6		0.6		0.7		0.8		1.3	ns
t _{HP}	Minimum Period	2.8		3.2		3.6		4.2		5.8		ns
f _{HMAX}	Maximum Frequency		357		313		278		238		172	MHz
Routed Arr	ay Clock Networks											
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		2.2		2.5		2.8		3.3		4.7	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		2.1		2.5		2.8		3.3		4.5	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		2.4		2.7		3.1		3.6		5.1	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		2.2		2.6		2.9		3.4		4.7	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		2.5		2.8		3.2		3.8		5.3	ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		2.4		2.8		3.1		3.7		5.2	ns
t _{RPWH}	Minimum Pulse Width High	1.4		1.6		1.8		2.1		2.9		ns
t _{RPWL}	Minimum Pulse Width Low	1.4		1.6		1.8		2.1		2.9		ns
t _{RCKSW}	Maximum Skew (Light Load)		1.0		1.1		1.3		1.5		2.1	ns
t _{RCKSW}	Maximum Skew (50% Load)		1.0		1.1		1.3		1.5		2.1	ns
t _{RCKSW}	Maximum Skew (100% Load)		1.0		1.1		1.3		1.5		2.1	ns

Note: *All –3 speed grades have been discontinued.

	2	08-Pin PQF	P		208-Pin PQFP					
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	A54SX72A Function	Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	A54SX72A Function	
1	GND	GND	GND	GND	36	I/O	I/O	I/O	I/O	
2	TDI, I/O	TDI, I/O	tdi, I/o	tdi, I/o	37	I/O	I/O	I/O	I/O	
3	I/O	I/O	I/O	I/O	38	I/O	I/O	I/O	I/O	
4	NC	I/O	I/O	I/O	39	NC	I/O	I/O	I/O	
5	I/O	I/O	I/O	I/O	40	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}	
6	NC	I/O	I/O	I/O	41	V _{CCA}	V _{CCA}	V _{CCA}	V _{CCA}	
7	I/O	I/O	I/O	I/O	42	I/O	I/O	I/O	I/O	
8	I/O	I/O	I/O	I/O	43	I/O	I/O	I/O	I/O	
9	I/O	I/O	I/O	I/O	44	I/O	I/O	I/O	I/O	
10	I/O	I/O	I/O	I/O	45	I/O	I/O	I/O	I/O	
11	TMS	TMS	TMS	TMS	46	I/O	I/O	I/O	I/O	
12	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}	47	I/O	I/O	I/O	I/O	
13	I/O	I/O	I/O	I/O	48	NC	I/O	I/O	I/O	
14	NC	I/O	I/O	I/O	49	I/O	I/O	I/O	I/O	
15	I/O	I/O	I/O	I/O	50	NC	I/O	I/O	I/O	
16	I/O	I/O	I/O	I/O	51	I/O	I/O	I/O	I/O	
17	NC	I/O	I/O	I/O	52	GND	GND	GND	GND	
18	I/O	I/O	I/O	GND	53	I/O	I/O	I/O	I/O	
19	I/O	I/O	I/O	V _{CCA}	54	I/O	I/O	I/O	I/O	
20	NC	I/O	I/O	I/O	55	I/O	I/O	I/O	I/O	
21	I/O	I/O	I/O	I/O	56	I/O	I/O	I/O	I/O	
22	I/O	I/O	I/O	I/O	57	I/O	I/O	I/O	I/O	
23	NC	I/O	I/O	I/O	58	I/O	I/O	I/O	I/O	
24	I/O	I/O	I/O	I/O	59	I/O	I/O	I/O	I/O	
25	NC	NC	NC	I/O	60	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}	
26	GND	GND	GND	GND	61	NC	I/O	I/O	I/O	
27	V _{CCA}	V _{CCA}	V _{CCA}	V _{CCA}	62	I/O	I/O	I/O	I/O	
28	GND	GND	GND	GND	63	I/O	I/O	I/O	I/O	
29	I/O	I/O	I/O	I/O	64	NC	I/O	I/O	I/O	
30	trst, I/O	TRST, I/O	trst, I/O	trst, I/O	65	I/O	I/O	NC	I/O	
31	NC	I/O	I/O	I/O	66	I/O	I/O	I/O	I/O	
32	I/O	I/O	I/O	I/O	67	NC	I/O	I/O	I/O	
33	I/O	I/O	I/O	I/O	68	I/O	I/O	I/O	I/O	
34	I/O	I/O	I/O	I/O	69	I/O	I/O	I/O	I/O	
35	NC	I/O	I/O	I/O	70	NC	I/O	I/O	I/O	

329-Pi	n PBGA						
Pin Number	A54SX32A Function	Pin Number	A54SX32A Function	Pin Number	A54SX32A Function	Pin Number	A54SX32A Function
D11	V _{CCA}	H1	I/O	L14	GND	P12	GND
D12	NC	H2	I/O	L20	NC	P13	GND
D13	I/O	H3	I/O	L21	I/O	P14	GND
D14	I/O	H4	I/O	L22	I/O	P20	I/O
D15	I/O	H20	V _{CCA}	L23	NC	P21	I/O
D16	I/O	H21	I/O	M1	I/O	P22	I/O
D17	I/O	H22	I/O	M2	I/O	P23	I/O
D18	I/O	H23	I/O	M3	I/O	R1	I/O
D19	I/O	J1	NC	M4	V _{CCA}	R2	I/O
D20	I/O	J2	I/O	M10	GND	R3	I/O
D21	I/O	J3	I/O	M11	GND	R4	I/O
D22	I/O	J4	I/O	M12	GND	R20	I/O
D23	I/O	J20	I/O	M13	GND	R21	I/O
E1	V _{CCI}	J21	I/O	M14	GND	R22	I/O
E2	I/O	J22	I/O	M20	V _{CCA}	R23	I/O
E3	I/O	J23	I/O	M21	I/O	T1	I/O
E4	I/O	K1	I/O	M22	I/O	T2	I/O
E20	I/O	К2	I/O	M23	V _{CCI}	T3	I/O
E21	I/O	К3	I/O	N1	I/O	T4	I/O
E22	I/O	К4	I/O	N2	TRST, I/O	T20	I/O
E23	I/O	K10	GND	N3	I/O	T21	I/O
F1	I/O	K11	GND	N4	I/O	T22	I/O
F2	TMS	K12	GND	N10	GND	T23	I/O
F3	I/O	K13	GND	N11	GND	U1	I/O
F4	I/O	K14	GND	N12	GND	U2	I/O
F20	I/O	K20	I/O	N13	GND	U3	V _{CCA}
F21	I/O	K21	I/O	N14	GND	U4	I/O
F22	I/O	K22	I/O	N20	NC	U20	I/O
F23	I/O	K23	I/O	N21	I/O	U21	V _{CCA}
G1	I/O	L1	I/O	N22	I/O	U22	I/O
G2	I/O	L2	I/O	N23	I/O	U23	I/O
G3	I/O	L3	I/O	P1	I/O	V1	V _{CCI}
G4	I/O	L4	NC	P2	I/O	V2	I/O
G20	I/O	L10	GND	P3	I/O	V3	I/O
G21	I/O	L11	GND	P4	I/O	V4	I/O
G22	I/O	L12	GND	P10	GND	V20	I/O
G23	GND	L13	GND	P11	GND	V21	I/O



256-Pin FBGA



Figure 3-7 • 256-Pin FBGA (Top View)

Note

For Package Manufacturing and Environmental information, visit Resource center at http://www.actel.com/products/rescenter/package/index.html.



Datasheet Information

List of Changes

The following table lists critical changes that were made in the current version of the document.

Previous Version	Changes in Current Version (v5.3)	Page			
v5.2	-3 speed grades have been discontinued.	N/A			
(June 2006)	The "SX-A Timing Model" was updated with –2 data.	2-14			
v5.1	RoHS information was added to the "Ordering Information".	ii			
February 2005	The "Programming" section was updated.	1-13			
v5.0	Revised Table 1 and the timing data to reflect the phase out of the -3 speed grade for the A54SX08A device.	i			
	The "Thermal Characteristics" section was updated.	2-11			
	The "176-Pin TQFP" was updated to add pins 81 to 90.	3-11			
	The "484-Pin FBGA" was updated to add pins R4 to Y26				
v4.0	The "Temperature Grade Offering" is new.	1-iii			
	The "Speed Grade and Temperature Grade Matrix" is new.	1-iii			
	"SX-A Family Architecture" was updated.	1-1			
	"Clock Resources" was updated.	1-5			
	"User Security" was updated.	1-7			
	"Power-Up/Down and Hot Swapping" was updated.	1-7			
	"Dedicated Mode" is new	1-9			
	Table 1-5 is new.	1-9			
	"JTAG Instructions" is new	1-10			
	"Design Considerations" was updated.	1-12			
	The "Programming" section is new.	1-13			
	"Design Environment" was updated.	1-13			
	"Pin Description" was updated.	1-15			
	Table 2-1 was updated.	2-1			
	Table 2-2 was updated.	2-1			
	Table 2-3 is new.	2-1			
	Table 2-4 is new.	2-1			
	Table 2-5 was updated.	2-2			
	Table 2-6 was updated.	2-2			
	"Power Dissipation" is new.	2-8			
	Table 2-11 was updated.	2-9			

Previous Version	Changes in Current Version (v5.3)	Page				
v4.0	Table 2-12 was updated.	2-11				
(continued)	The was updated.	2-14				
	The "Sample Path Calculations" were updated.	2-14				
	Table 2-13 was updated.	2-17				
	Table 2-13 was updated.	2-17				
	All timing tables were updated.	2-18 to 2-52				
v3.0	The "Actel Secure Programming Technology with FuseLock™ Prevents Reverse Engineering and Design Theft" section was updated.					
	The "Ordering Information" section was updated.	1-ii				
	The "Temperature Grade Offering" section was updated.	1-iii				
	The Figure 1-1 • SX-A Family Interconnect Elements was updated.	1-1				
	The ""Clock Resources" section" was updated	1-5				
	The Table 1-1 • SX-A Clock Resources is new.	1-5				
	The "User Security" section is new.	1-7				
	The "I/O Modules" section was updated.	1-7				
	The Table 1-2 • I/O Features was updated.	1-8				
	The Table 1-3 • I/O Characteristics for All I/O Configurations is new.	1-8				
	The Table 1-4 • Power-Up Time at which I/Os Become Active is new	1-8				
	The Figure 1-12 • Device Selection Wizard is new.	1-9				
	The "Boundary-Scan Pin Configurations and Functions" section is new.	1-9				
	The Table 1-9 • Device Configuration Options for Probe Capability (TRST Pin Reserved) is new.	1-11				
	The "SX-A Probe Circuit Control Pins" section was updated.	1-12				
	The "Design Considerations" section was updated.	1-12				
	The Figure 1-13 • Probe Setup was updated.	1-12				
	The Design Environment was updated.	1-13				
	The Figure 1-13 • Design Flow is new.	1-11				
	The "Absolute Maximum Ratings*" section was updated.	1-12				
	The "Recommended Operating Conditions" section was updated.	1-12				
	The "Electrical Specifications" section was updated.	1-12				
	The "2.5V LVCMOS2 Electrical Specifications" section was updated.	1-13				
	The "SX-A Timing Model" and "Sample Path Calculations" equations were updated.	1-23				
	The "Pin Description" section was updated.	1-15				
v2.0.1	The "Design Environment" section has been updated.	1-13				
	The "I/O Modules" section, and Table 1-2 • I/O Features have been updated.	1-8				
	The "SX-A Timing Model" section and the "Timing Characteristics" section have new timing numbers.	1-23				

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